

A trap detector for precise measurements of optical radiation power

Kübarsepp, Toomas; Kärhää, Petri BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 195-200: ill

Actual research topics in mechatronics system design

Glesner, M.; Herpel, H.-J.; Kirschbaum, A.; Windirsch, P. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 85-91: ill

Alternative graphs as a mathematical tool and knowledge representation for diagnosis purposes in digital systems

Ubar, Raimund-Johannes BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 285-292: ill

An approach to model development for embedded testing

Timohovich, E. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 353-358

An interesting and effective code for error-correcting in mass-storage devices

Szepessy, Andras BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 331-337

Assurance of gain stability of spaceborne teleradiometers

Veismann, Uno; Min, Mart BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 179-185: ill

A CAD system for teaching digital test

Ubar, Raimund-Johannes; Ivask, Eero; Paomets, Priidu; Raik, Jaan BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 369-372: ill

Chaos in electronic circuits

Lindberg, Erik BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 29-37: ill

Complementary Darlington circuit

Männama, Vello BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 223-228: ill

Constraints analysis in hierarchical test generation for digital systems

Ubar, Raimund-Johannes; Krupnova, Helena BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 313-318: ill

Design and application of lock-in instruments

Min, Mart BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 95-104: ill

Different ways for optimization of settling time of the 3rd order phase locked loop

Tammemägi, Jaak BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 239-243: ill

Direct sequence spread spectrum digital radio

Kerek, Daniel; Saluvere, Teet; Tenhunen, Hannu BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 159-167: ill

Elektrodenübergangs impedanz bei bioelektrischen Messungen

Märting, Hannes BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / S. 147-150: ill

Elements of noise modeling in bipolar semiconductor devices

Blum, Alfons BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 11-27

Experimental study of ultrasonic microprocessor - based heat meters

Ragauskas, A.; Pamakstis, V. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 141-145: ill

Fault aliasing of signature analyzers

Kemnitz, Günter; Kärger, Reinhard BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 339-346: ill

A global methodology for test program generation starting from high level specifications

Storojev, Sergei; Leveugle, Regis; Saucier, Gabriele BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 305-311: ill https://www.ester.ee/record=b2150914*est

Hierarchical test generation for finite state machines

Brik, Marina; Ubar, Raimund-Johannes BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 319-324: ill

Identification of signal's sine-wave dominants using analysis of level crossings

Ronk, Ants BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 233-238: ill

Infrared and near-infrared Fourier spectrometer PFS 2000 for analytical research

Tönnisson, T.; Lipping, Kalle; Pelt, Jaan; Raadi, G.; Randmets, R. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 169-172

Information techniques for sensor- and microsystems

Holmer, R.; Tränkler, Hans-Rolf BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 39-50: ill

Intelligence system for design and investigation mechanical values sensors

Shmakov, E.M.; Matveev, V.A.; Molotkov, S.V. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 261-269: ill

Intelligent diagnostic centers: a new way to distributed fault-tolerance

Varkonyi-Koczy, Annamaria R.; Tilly, K.; Dobrowiecki, Tadeusz; Vadasz, B.; Kiss, I. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 365-368: ill

Low-noise CMOS-charge amplifier for a silicon strip detector

Grönlund, Marko BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 217-222: ill

MCM-test

Magnhagen, Bengt; Linden, Henric BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 297-304: ill

Measuring electrical bio-impedance - some practical aspects

Eek, Andres; Ollmar, S. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / lk. 117-124: ill

A method for identification dynamic parameters of mixed signal circuits

Zagursky, V.; Semyonova, N.; Gertners, A. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 211-215 https://www.ester.ee/record=b2150914*est

A method for testing dynamic characteristics of analog-digital converters in spectral domain

Zagursky, V.; Semyonova, N.; Gertners, A. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 207-210 https://www.ester.ee/record=b2150914*est

Modeling of blood flow measurement system elements

Adaškevičius, R.; Kopustinskas, A. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 125-131: ill

Monitoring and problems of short-term prognosis in the field of plants protection

Butkevicius, R.; Žilinskas, R. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 277-281

New method and electronic system for the human brain hydrodynamic diagnosing

Ragauskas, A.; Daubaris, G. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 133-139: ill

Non-invasive measurement and determination of structural vibration modes of precision controlled motion systems

Kaušinis, Saulius; Isoda, Antanas BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 271-272: ill

Parallel implementation of the recursive discrete Fourier transformation

Varkonyi-Koczy, Annamaria R. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 111-115

PLL based scanner stabilizer

Lipping, Kalle BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 173-177: ill

Sensors and systems for product data and product identification in CIM

Henoch, Bengt BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 51-64 : ill

Simulation and automated test development system for digital devices

Birger, Alexander BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 293-295

Software development for programmable instrumentation

Usk, Aivar BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 255-260: ill

Standards for radiometric calibration of electro-optical devices in Estonia

Veismann, Uno; Pehk, M.; Kübarsepp, Toomas BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 187-193: ill

Stepwise Lock-In Signal Conversion

Parve, Toomas BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 245-254: ill

Synchronous detector with MOSFETs

Kuusik, Alar BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 229-232: ill

Synthesis of hierarchically testable FSM networks

Kasirova, Lilia; Keevallik, Andres; Kruus, Margus BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 347-352: ill

Test generation for control faults in digital systems

Dušina, Julia; Brik, Marina BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 325-330: ill

The analysis of integrating sigma-delta ADC noise

Gutnikov, V.S.; Krivchenko, T.I. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 201-206: ill

The contribution of the artificial intelligence to the measurement science

Dobrowiecki, Tadeusz; Louage, Frank; Pataki, Bela BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 105-110: ill

The method of conformance testing for presentation data transfer syntax

Shevelkov, V. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 359-364: ill

The realization of the synchronous signal conditioning and demodulating system

Land, Raul BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 151-158: ill

Trends in artificial intelligence applications for real-time control : (a speculative study)

Mõtus, Leo BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 71-83

Ultrasonic sensors - an intelligent sensor principle for many applications

Magori, V. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 65-70: ill